Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/687,048	LEE ET AL.	
Examiner	Art Unit	-
DiLinh Nauven	2814	

SEARCHED						
Class		Subclass	Date		Examiner	
257		666	6/7/2006		DLN	
		669-670				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
257	666	6/7/2006	DLN		
257	690	6/7/2006	DLN		
257	787	6/7/2006	DLN		
See Interference Searched History		6/7/2006	DLN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Search (USPGPUB, USPAT, EPO, JPO, DERWENT)	6/7/2006	DLN		